

Notice of References Cited

Application/Control No.

10/025,402

Applicant(s)/Patent Under

Reexamination
STOL ET AL.

Examiner

Lynne Edmondson

Art Unit

1725

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,213,379	04-2001	Takeshita et al.	228/112.1
*	B	US-6,344,117	02-2002	Enomoto et al.	204/286.09
*	C	US-5,975,406	11-1999	Mahoney et al.	228/112.1
*	D	US-4,676,707	06-1987	Cearlock et al.	411/510
*	E	US-2002/0121319	09-2002	Chakrabarti et al.	148/694
*	F	US-4,144,110	03-1979	Luc, Jane	156/73.5
*	G	US-6,227,433	06-2001	Waldron et al.	228/112.1
*	H	US-5,769,306	06-1998	Colligan, Kevin James	228/112.1
*	I	US-5,460,317	10-1995	Thomas et al.	228/112.1
*	J	US-6,067,839	05-2000	Xie, Max	72/391.8
*	K	US-6,095,395	08-2000	Fix, Jr., John William	228/2.3
*	L	US-3,477,115	11-1969	Martins	228/114.5
*	M	US-6,050,474	04-2000	Aota et al.	228/112.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	GB-2306368-A	05-1997	UK	Thomas et al.	
*	O	EP-0337813-A1	10-1989	EPO	Jenkins	
*	P	JP-11-201177-A	07-1999	Japan	Aicello Chem Co Ltd.	
*	Q	JP-2000-9122-A	01-2000	Japan	Nippon Stud Welding KK	
*	R	WO 99/39861-A1	08-1999	WIPO	Midling et al.	
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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